To our customers,

Old Company Name in Catalogs and Other Documents

On April 1st, 2010, NEC Electronics Corporation merged with Renesas Technology Corporation, and Renesas Electronics Corporation took over all the business of both companies. Therefore, although the old company name remains in this document, it is a valid Renesas Electronics document. We appreciate your understanding.

Renesas Electronics website: http://www.renesas.com

April 1st, 2010
Renesas Electronics Corporation

Issued by: Renesas Electronics Corporation (http://www.renesas.com)

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RENESAS

DATA SHEET

RENESAS

MOS FIELD EFFECT TRANSISTOR
2SK3639

Phase-out/Discontinued

SWITCHING
N-CHANNEL POWER MOS FET

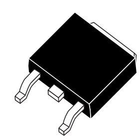
DESCRIPTION

The 2SK3639 is N-channel MOS FET device that features a low on-state resistance and excellent switching characteristics, and designed for low voltage high current applications such as DC/DC converter with synchronous rectifier.

ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3639-ZK	TO-252 (MP-3ZK)

(TO-252)



FEATURES

- Low on-state resistance
  $R_{DS(on)1}$ = 5.5 mΩ MAX. (V_{GS} = 10 V, I_D = 32 A)
  $R_{DS(on)2}$ = 8.5 mΩ MAX. (V_{GS} = 4.5 V, I_D = 32 A)
- Low C_{iss}: C_{iss} = 2400 pF TYP.

ABSOLUTE MAXIMUM RATINGS (T_A = 25°C)

Drain to Source Voltage (V_{GS} = 0 V)	V_{DSS}	20	V
Gate to Source Voltage (V_{DS} = 0 V)	V_{GSS}	±20	V
Drain Current (DC) (T_C = 25°C)	$I_{D(DC)}$	±64	A
Drain Current (pulse) Note	$I_{D(pulse)}$	±256	A
Total Power Dissipation (T_C = 25°C)	P_{T1}	40	W
Total Power Dissipation	P_{T2}	1.0	W
Channel Temperature	T_{ch}	150	°C
Storage Temperature	T_{stg}	–55 to +150	°C

Note PW ≤ 10 μs, Duty Cycle ≤ 1%

The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version.
Not all products and/or types are available in every country. Please check with an NEC Electronics sales representative for availability and additional information.

Document No. D15967EJ3V0DS00 (3rd edition)
Date Published January 2005 NS CP(K)
Printed in Japan

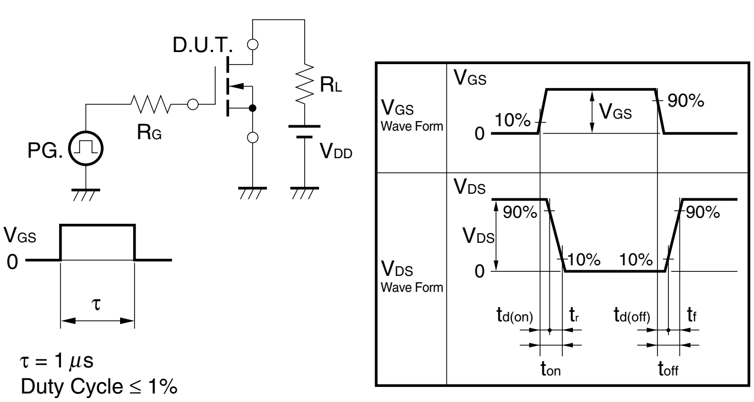
The mark ★ shows major revised points.

ELECTRICAL CHARACTERISTICS (T_A = 25°C)

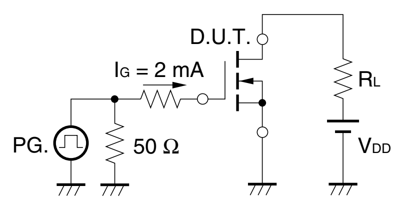
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = 20 V, V_{GS} = 0 V			10	μA
Gate Leakage Current	I_{GSS}	V_{GS} = ±20 V, V_{DS} = 0 V			±100	nA
Gate Cut-off Voltage	$V_{GS(off)}$	V_{DS} = 10 V, I_D = 1 mA	1.5		2.5	V
Forward Transfer Admittance Note	$\|y_{fs}\|$	V_{DS} = 10 V, I_D = 32 A	19	39		S
Drain to Source On-state Resistance Note	$R_{DS(on)1}$	V_{GS} = 10 V, I_D = 32 A		4.4	5.5	mΩ
	$R_{DS(on)2}$	V_{GS} = 4.5 V, I_D = 32 A		5.8	8.5	mΩ
Input Capacitance	C_{iss}	V_{DS} = 10 V		2400		pF
Output Capacitance	C_{oss}	V_{GS} = 0 V		970		pF
Reverse Transfer Capacitance	C_{rss}	f = 1 MHz		350		pF
Turn-on Delay Time	$t_{d(on)}$	V_{DD} = 10 V, I_D = 32 A		13		ns
Rise Time	t_r	V_{GS} = 10 V		14		ns
Turn-off Delay Time	$t_{d(off)}$	R_G = 10 Ω		71		ns
Fall Time	t_f			22		ns
Total Gate Charge	Q_G	V_{DD} = 16 V		45		nC
Gate to Source Charge	Q_{GS}	V_{GS} = 10 V		7.6		nC
Gate to Drain Charge	Q_{GD}	I_D = 64 A		11		nC
Body Diode Forward Voltage Note	$V_{F(S-D)}$	I_F = 64 A, V_{GS} = 0 V		0.96		V
Reverse Recovery Time	t_{rr}	I_F = 64 A, V_{GS} = 0 V		40		ns
Reverse Recovery Charge	Q_{rr}	di/dt = 100 A/μs		35		nC

Note Pulsed: PW ≤ 350 μs, Duty Cycle ≤ 2%

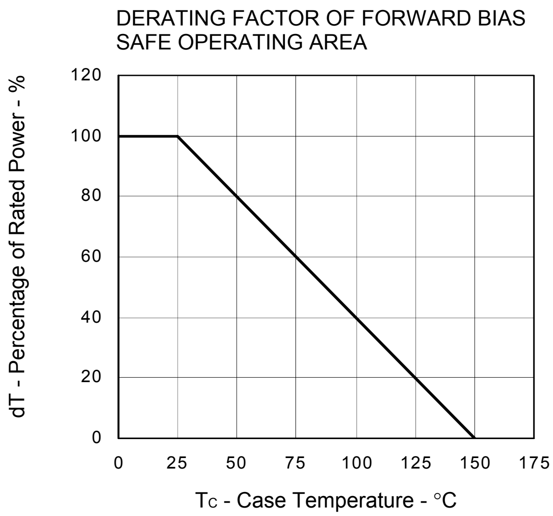
TEST CIRCUIT 1 SWITCHING TIME

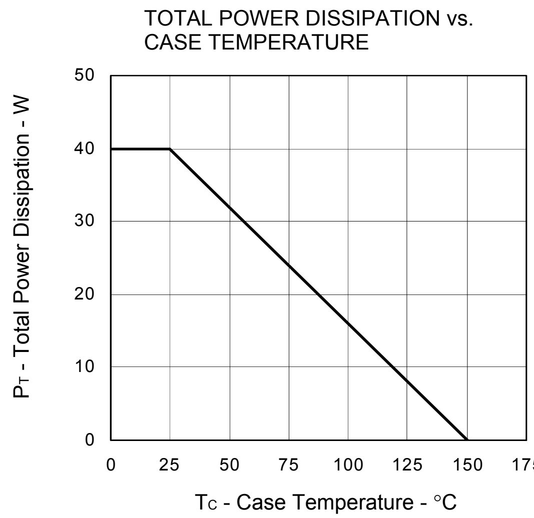


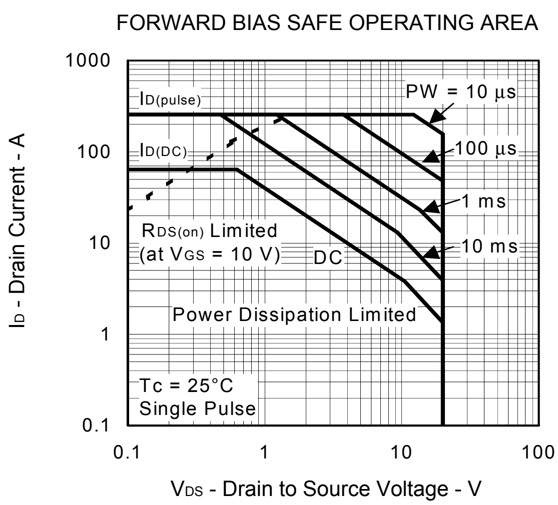
TEST CIRCUIT 2 GATE CHARGE

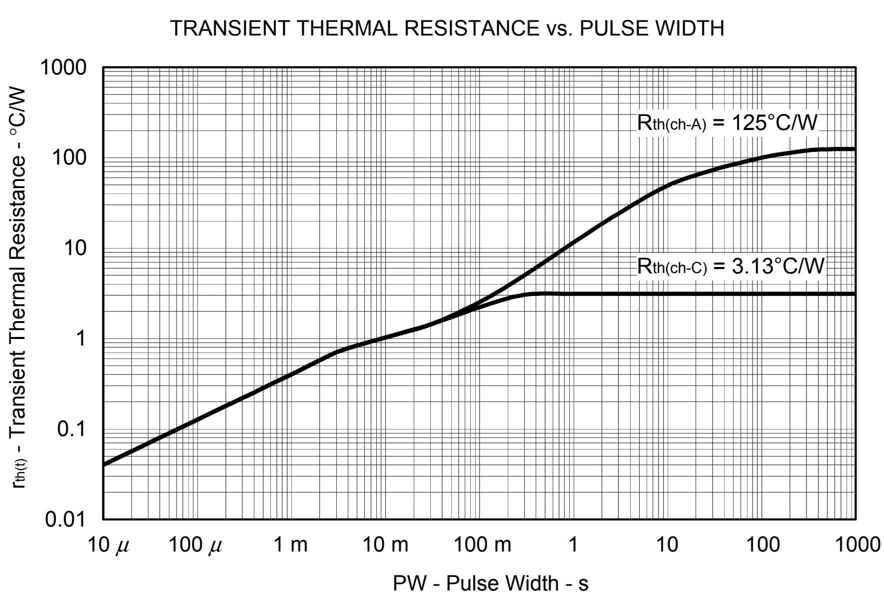


TYPICAL CHARACTERISTICS (T_A = 25°C)

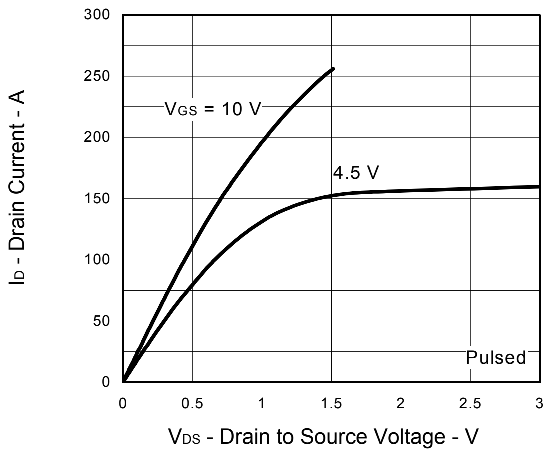




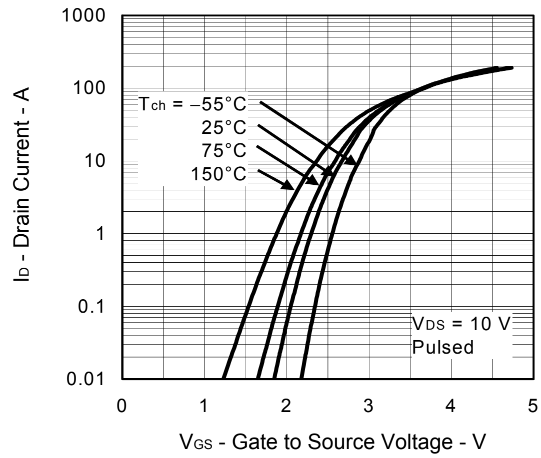




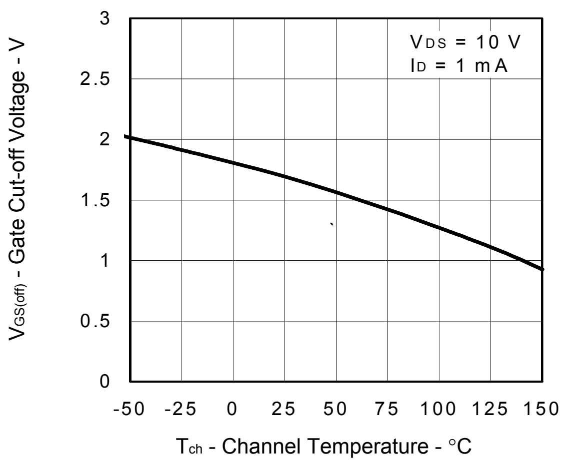
DRAIN CURRENT vs.
DRAIN TO SOURCE VOLTAGE



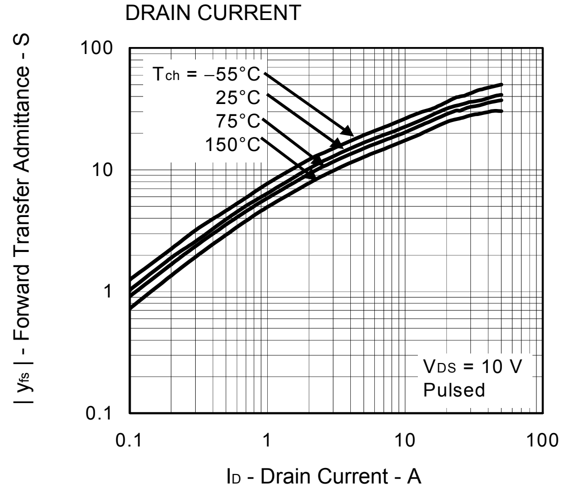
FORWARD TRANSFER CHARACTERISTICS



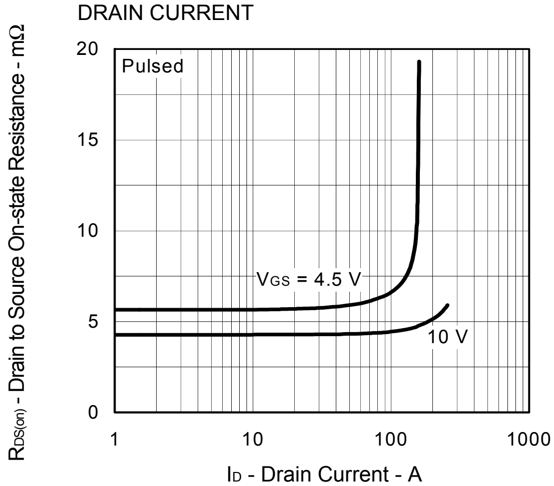
GATE CUT-OFF VOLTAGE vs.
CHANNEL TEMPERATURE



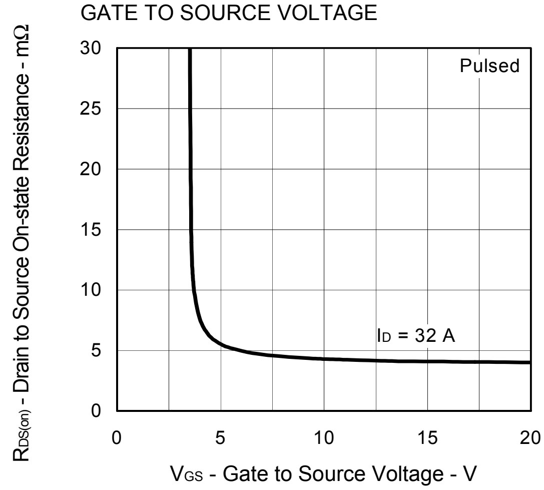
FORWARD TRANSFER ADMITTANCE vs.
DRAIN CURRENT



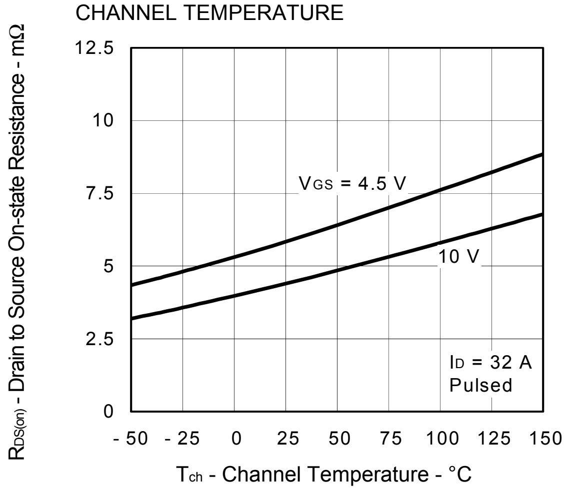
DRAIN TO SOURCE ON-STATE RESISTANCE vs.
DRAIN CURRENT



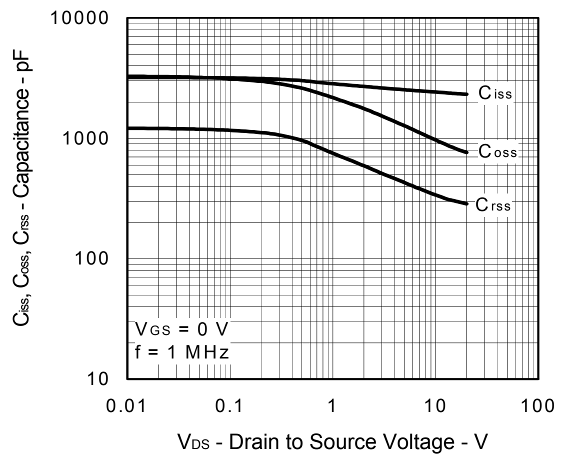
DRAIN TO SOURCE ON-STATE RESISTANCE vs.
GATE TO SOURCE VOLTAGE



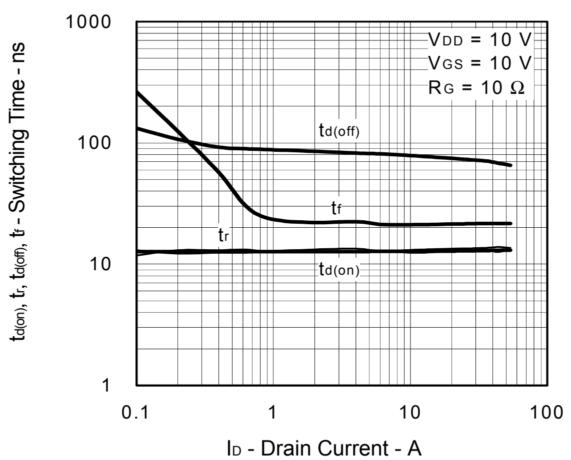
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



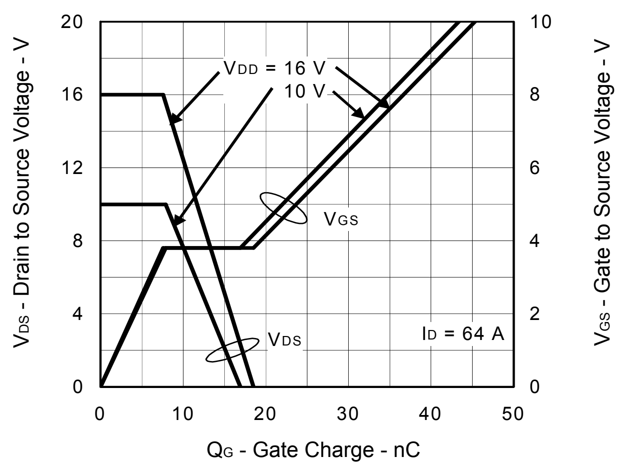
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



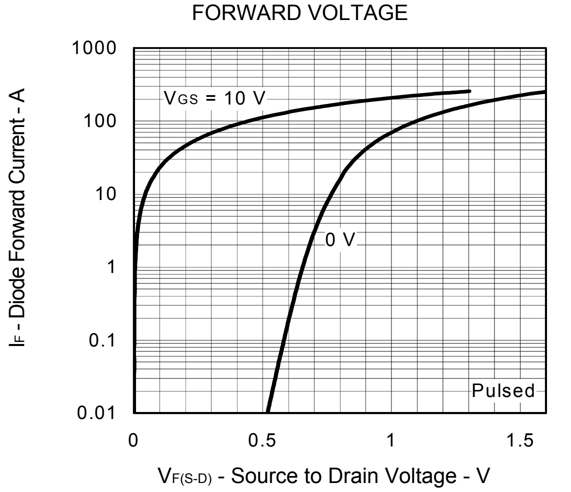
SWITCHING CHARACTERISTICS



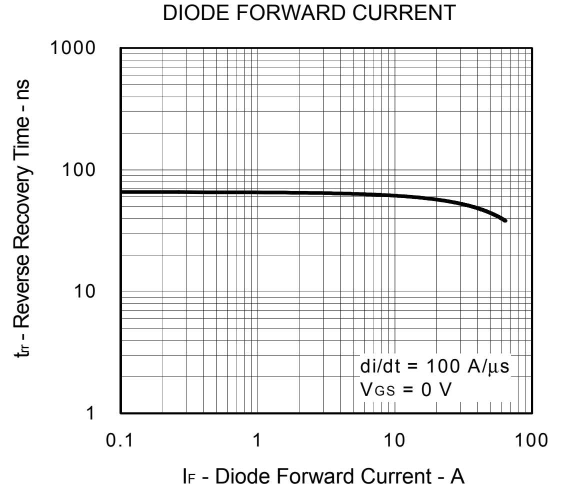
DYNAMIC INPUT/OUTPUT CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE

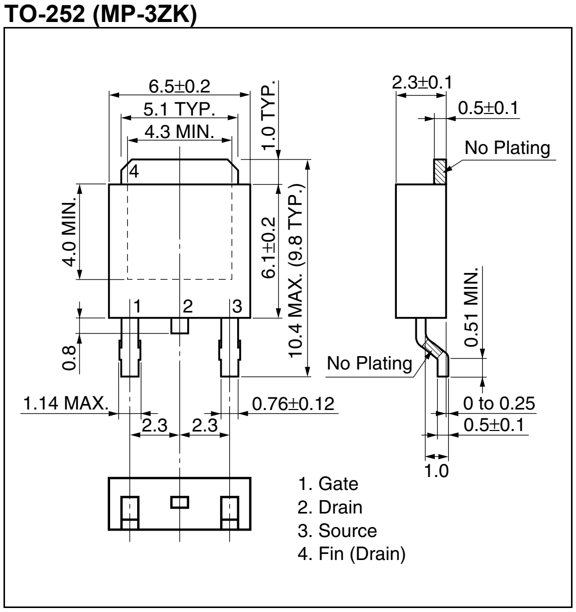


REVERSE RECOVERY TIME vs. DIODE FORWARD CURRENT

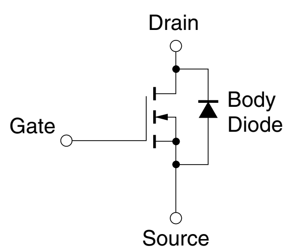


★ PACKAGE DRAWING (Unit: mm)

TO-252 (MP-3ZK)



EQUIVALENT CIRCUIT



Remark Strong electric field, when exposed to this device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.